### **ON Semiconductor**

#### Is Now



To learn more about onsemi™, please visit our website at www.onsemi.com

onsemi and ONSEMI. and other names, marks, and brands are registered and/or common law trademarks of Semiconductor Components Industries, LLC dba "onsemi" or its affiliates and/or subsidiaries in the United States and/or other countries. onsemi owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of onsemi product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. onsemi reserves the right to make changes at any time to any products or information herein is provided "as-is" and onsemi makes no warranty, representation or guarantee regarding the accuracy of the information, product features, availability, functionality, or suitability of its products for any particular purpose, nor does onsemi assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using onsemi products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by onsemi. "Typical" parameters which may be provided in onsemi data sheets and/ or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. onsemi does not convey any license under any of its intellectual property rights nor the rights of others. onsemi products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use onsemi products for any such unintended or unauthorized application,



ON Semiconductor®

### **FDS6982AS**

## Dual Notebook Power Supply N-Channel PowerTrench® SyncFET<sup>™</sup> **General Description**

The FDS6982AS is designed to replace two single SO-8 MOSFETs and Schottky diode in synchronous DC:DC power supplies that provide various peripheral voltages for notebook computers and other battery powered electronic devices. FDS6982AS contains two unique 30V, N-channel, logic level, PowerTrench MOSFETs designed to maximize power conversion efficiency. The high-side switch (Q1) is designed with specific emphasis on reducing switching losses while the low-side switch (Q2) is optimized to reduce Q2 also includes an integrated conduction losses. Schottky diode using ON Semiconductor's monolithic SyncFET technology.

#### **Applications**

Notebook



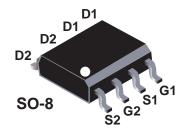
Q2: Optimized to minimize conduction losses Includes SyncFET Schottky body diode

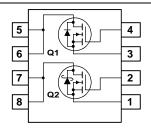
8.6A, 30V 
$$R_{DS(on)}$$
 max= 13.5m $\Omega$  @  $V_{GS}$  = 10V  $R_{DS(on)}$  max= 16.5m $\Omega$  @  $V_{GS}$  = 4.5V

- Low gate charge (21nC typical)
- Optimized for low switching losses

6.3A, 30V 
$$R_{DS(on)}$$
 max= 28.0m $\Omega$  @  $V_{GS}$  = 10V 
$$R_{DS(on)}$$
 max= 35.0m $\Omega$  @  $V_{GS}$  = 4.5V

Low gate charge (11nC typical)





#### Absolute Maximum Ratings T<sub>A</sub> = 25°C unless otherwise noted

Symbol	Parameter		Q2	Q1	Units
V <sub>DSS</sub>	Drain-Source Voltage		30	30	V
V <sub>GSS</sub>	Gate-Source Voltage		±20	±20	V
I <sub>D</sub>	Drain Current - Continuous	(Note 1a)	8.6	6.3	Α
	- Pulsed		30	20	
P <sub>D</sub>	Power Dissipation for Dual Operation		2	W	
	Power Dissipation for Single Operation	(Note 1a)	1.	6	
	(Note 1b)		1		
		(Note 1c)	0.	9	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range		–55 to	+150	°C

#### **Thermal Characteristics**

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	78	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	40	°C/W

#### **Package Marking and Ordering Information**

Device Marking	Device	Reel Size	Tape width	Quantity
FDS6982AS	FDS6982AS	13"	12mm	2500 units

Symbol	Parameter	Test Conditions	Type	Min	Тур	Max	Units
Off Cha	racteristics					•	
BV <sub>DSS</sub>	Drain-Source Breakdown	$V_{GS} = 0 \text{ V}, \qquad I_D = 1 \text{ mA}$	Q2	30			V
500	Voltage	$V_{GS} = 0 \text{ V}, \qquad I_{D} = 250 \text{ uA}$	Q1	30			
ΔBV <sub>DSS</sub>	Breakdown Voltage	I <sub>D</sub> = 1 mA, Referenced to 25°C	Q2		28		mV/°C
$\Delta T_{J}$	Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced to 25°C	Q1		24		
I <sub>DSS</sub>	Zero Gate Voltage Drain	$V_{DS} = 24 \text{ V},  V_{GS} = 0 \text{ V}$	Q2			500	μА
	Current		Q1			1	
$I_{GSS}$	Gate-Body Leakage	$V_{GS} = \pm 20 \text{ V},  V_{DS} = 0 \text{ V}$	Q2 Q1			±100	nA
On Cha	racteristics (Note 2)					1	II.
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 1 \text{ mA}$	Q2	1	1.4	3	V
V GS(th)	Gate Tilleshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 1 \text{ mA}$ $V_{DS} = V_{GS}$ , $I_D = 250 \mu\text{A}$	Q2 Q1	1	1.9	3	\ \ \
$\Delta V_{GS(th)}$	Gate Threshold Voltage	I <sub>D</sub> = 1 mA, Referenced to 25°C	Q2		-3.1		mV/°C
$\Delta T_{J}$	Temperature Coefficient						IIIV/ C
-		I <sub>D</sub> = 250 uA, Referenced to 25°C	Q1		-4.3		
R <sub>DS(on)</sub>	Static Drain-Source	$V_{GS} = 10 \text{ V}, I_D = 8.6 \text{ A}$	Q2		11	13.5	mΩ
	On-Resistance	$V_{GS} = 10 \text{ V}, I_D = 8.6 \text{ A}, T_J = 125^{\circ}\text{C}$			16	20.0	
		$V_{GS} = 4.5 \text{ V}, I_D = 7.5 \text{ A}$			13	16.5	
		$V_{GS} = 10 \text{ V}, I_D = 6.3 \text{ A}$	Q1		20	28	
		$V_{GS} = 10 \text{ V}, I_D = 6.3 \text{ A}, T_J = 125^{\circ}\text{C}$			26	33	
	0.011.0.1	$V_{GS} = 4.5 \text{ V}, I_D = 5.6 \text{ A}$			25	35	Α
I <sub>D(on)</sub>	On-State Drain Current	$V_{GS} = 10 \text{ V}, \qquad V_{DS} = 5 \text{ V}$	Q2 Q1	30 20			A
~	Forward Transconductance	$V_{DS} = 5 \text{ V}, \qquad I_{D} = 8.6 \text{ A}$	Q1 Q2	20	32		S
<b>g</b> <sub>FS</sub>	Forward Transconductance	$V_{DS} = 5 \text{ V}, \qquad I_D = 6.3 \text{ A}$ $V_{DS} = 5 \text{ V}, \qquad I_D = 6.3 \text{ A}$	Q2 Q1		19		"
Dynami	c Characteristics	1,103 6.1, 10 6.67.				1	1
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 0 V,	Q2		1250		pF
OISS	mpat Sapasitanos	f = 1.0 MHz	Q1		610		P.
Coss	Output Capacitance		Q2		410		pF
			Q1		180		•
C <sub>rss</sub>	Reverse Transfer Capacitance		Q2		130		рF
			Q1		85		
$R_G$	Gate Resistance	$V_{GS} = 15 \text{mV},  f = 1.0 \text{ MHz}$	Q2		1.4		Ω
			Q1		2.2		
Switchi	ng Characteristics (Note 2	2)					
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = 15 \text{ V},  I_{D} = 1 \text{ A},$	Q2		9	18	ns
-(- /	-	$V_{GS}$ = 10V, $R_{GEN}$ = 6 $\Omega$	Q1		10	20	
t <sub>r</sub>	Turn-On Rise Time		Q2		6	12	ns
			Q1		7	14	
$t_{d(off)}$	Turn-Off Delay Time		Q2		27	44	ns
	T 0" F " T'		Q1		24	39	
$t_{f}$	Turn-Off Fall Time		Q2 Q1		11 3	20	ns
t	Turn-On Delay Time	V <sub>DD</sub> = 15 V, I <sub>D</sub> = 1 A,	Q2		12	6 22	ne
$t_{d(on)}$	Tani-On Dolay Time	$V_{GS} = 4.5V$ , $R_{GEN} = 6 \Omega$	Q2 Q1		12	22	ns
t <sub>r</sub>	Turn-On Rise Time	- 1.00 1.00 1.10 0 1.2	Q2		13	23	ns
7	1		Q1		14	25	
t <sub>d(off)</sub>	Turn-Off Delay Time	1	Q2	İ	19	34	ns
· /	•		Q1		15	27	<u> </u>
t <sub>f</sub>	Turn-Off Fall Time		Q2		10	20	ns
	1	Ī	Q1	Ī	5	10	Ī

## **Electrical Characteristics** (continued)

T<sub>A</sub> = 25°C unless otherwise noted

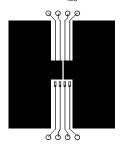
Symbol	Parameter	Test Conditions	Туре	Min	Тур	Max	Units		
Switching Characteristics (Note 2)									
$Q_{g(TOT)}$		Q2: V <sub>DS</sub> = 15 V, I <sub>D</sub> = 11.5A	Q2 Q1		21 11	30 15	nC		
$Q_g$	Total Gate Charge at Vgs=5V	Q1: V <sub>DS</sub> = 15 V, I <sub>D</sub> = 6.3A	Q2 Q1		12 6	16 9	nC		
$Q_{gs}$	Gate-Source Charge		Q2 Q1		3.1 1.8		nC		
$Q_{gd}$	Gate-Drain Charge		Q2 Q1		3.6 2.4		nC		

**Drain-Source Diode Characteristics and Maximum Ratings** 

Is	Maximum Continuous Drain-Source Diode Forward Current			Q2		3.0	Α
				Q1		1.3	
Trr	Reverse Recovery Time	I <sub>F</sub> = 11.5 A,		Q2	19		ns
Q <sub>rr</sub>	Reverse Recovery Charge	$d_{iF}/d_t = 300 \text{ A/}\mu\text{s}$	(Note 3)		12		nC
Trr	Reverse Recovery Time	I <sub>F</sub> = 6.3 A,		Q1	20		ns
Qrr	Reverse Recovery Charge	$d_{iF}/d_t = 100 \text{ A/}\mu\text{s}$	(Note 3)		9		nC
$V_{SD}$	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 3 \text{ A}$ $V_{GS} = 0 \text{ V}, I_S = 6 \text{ A}$ $V_{GS} = 0 \text{ V}, I_S = 1.3 \text{ A}$	(Note 2) (Note 2) (Note 2)	Q2 Q2 Q1	0.5 0.6 0.8	0.7 1.0 1.2	V

#### Notes:

1. R<sub>BJA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>BJC</sub> is guaranteed by design while R<sub>BCA</sub> is determined by the user's board design.



a) 78°C/W when mounted on a 0.5in² pad of 2 oz copper



125°C/W when mounted on a 0.02 in<sup>2</sup> pad of 2 oz copper



c) 135°C/W when mounted on a minimum pad.

Scale 1 : 1 on letter size paper

- 2. Pulse Test: Pulse Width <  $300\mu$ s, Duty Cycle < 2.0%
- 3. See "SyncFET Schottky body diode characteristics" below.

### Typical Characteristics: Q2

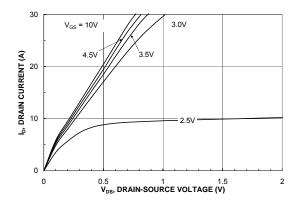


Figure 1. On-Region Characteristics.

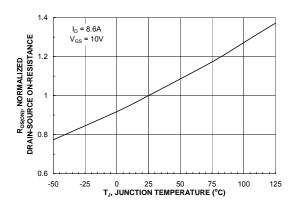


Figure 3. On-Resistance Variation with Temperature.

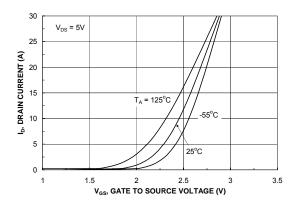


Figure 5. Transfer Characteristics.

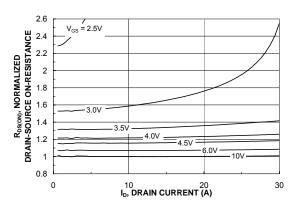


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

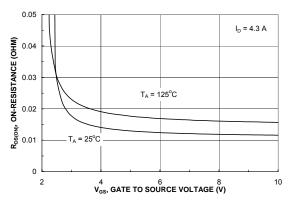


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

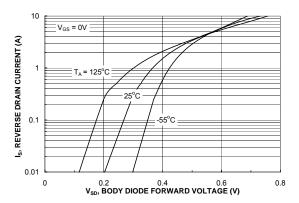
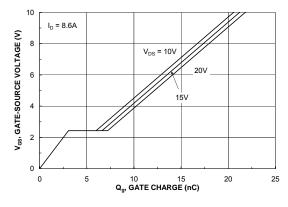


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

### Typical Characteristics: Q2



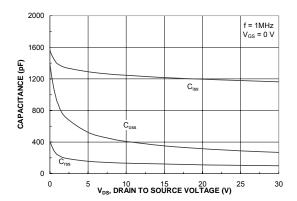
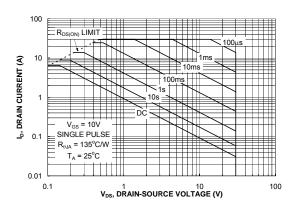


Figure 7. Gate Charge Characteristics.





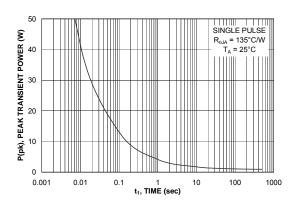


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

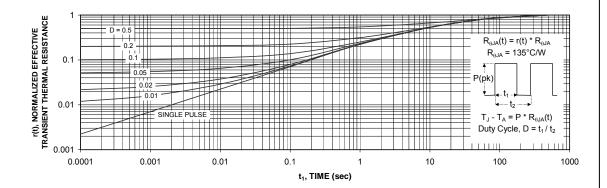


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.

### **Typical Characteristics Q1**

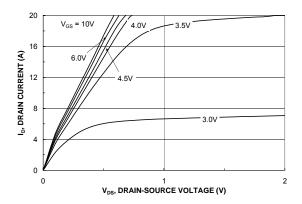


Figure 12. On-Region Characteristics.

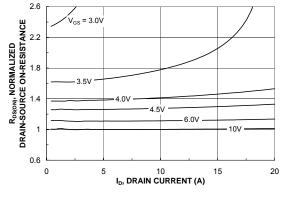


Figure 13. On-Resistance Variation with Drain Current and Gate Voltage.

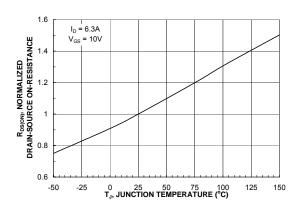


Figure 14. On-Resistance Variation with Temperature.

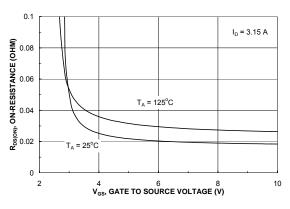


Figure 15. On-Resistance Variation with Gate-to-Source Voltage.

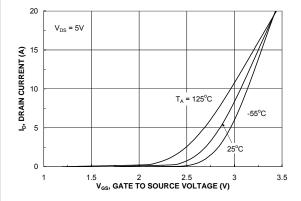


Figure 16. Transfer Characteristics.

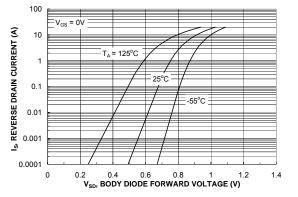
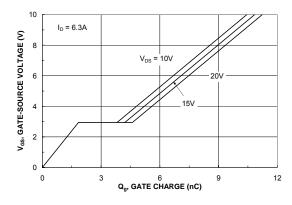


Figure 17. Body Diode Forward Voltage Variation with Source Current and Temperature.

### **Typical Characteristics Q1**



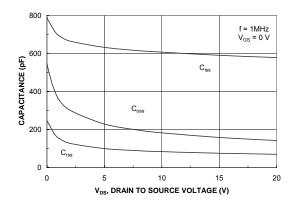
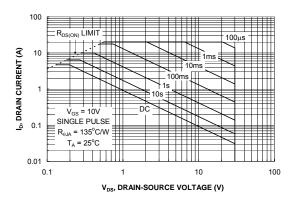


Figure 18. Gate Charge Characteristics.





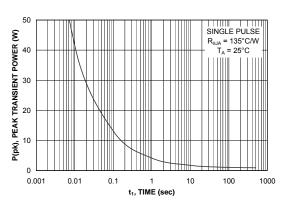


Figure 20. Maximum Safe Operating Area.

Figure 21. Single Pulse Maximum Power Dissipation.

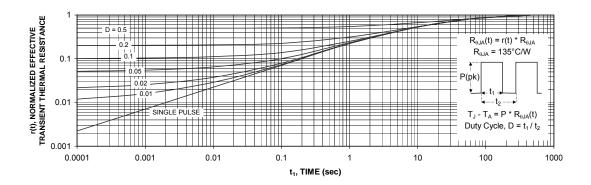


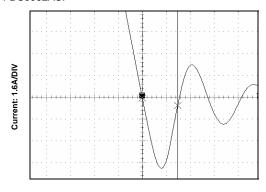
Figure 22. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.

#### Typical Characteristics (continued)

# SyncFET Schottky Body Diode Characteristics

ON Semiconductor's SyncFET process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. **Figure 23** shows the reverse recovery characteristic of the FDS6982AS.



Time: 10nS/DIV

Figure 23. FDS6982AS SyncFET body diode reverse recovery characteristic.

For comparison purposes, **Figure 24** shows the reverse recovery characteristics of the body diode of an equivalent size MOSFET produced without SyncFET (FDS6982).

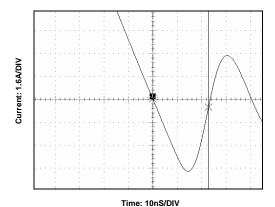


Figure 24. Non-SyncFET (FDS6982) body diode reverse recovery characteristic.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

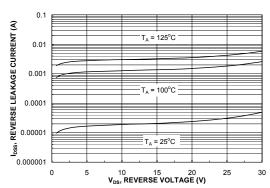
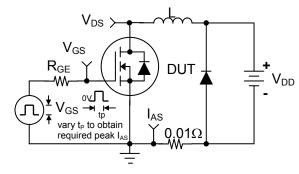


Figure 25. SyncFET body diode reverse leakage versus drain-source voltage and temperature

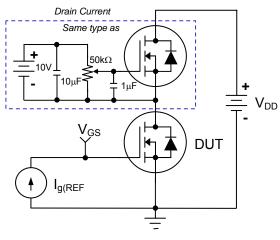
## **Typical Characteristics**



BV<sub>DSS</sub>
V<sub>DS</sub>
V<sub>DD</sub>
V<sub>DD</sub>

Figure 26. Unclamped Inductive Load Test Circuit

Figure 27. Unclamped Inductive Waveforms



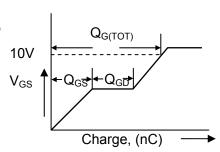
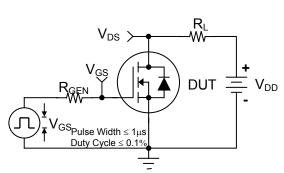


Figure 28. Gate Charge Test Circuit

Figure 29. Gate Charge Waveform



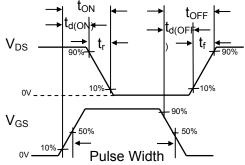


Figure 30. Switching Time Test Circuit

Figure 31. Switching Time Waveforms

ON Semiconductor and III) are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at <a href="www.onsemi.com/site/pdf/Patent-Marking.pdf">www.onsemi.com/site/pdf/Patent-Marking.pdf</a>. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages.

Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and hold ON Semiconductor and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that ON Semiconductor was negligent regarding the design or manufacture of the part. ON Semiconductor is an Equal Opportunity/Affirmative Action Employer. This literature is subject to all applicable copyright laws and is not for resale in any manner.

#### **PUBLICATION ORDERING INFORMATION**

#### LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor 19521 E. 32nd Pkwy, Aurora, Colorado 80011 USA Phone: 303-675-2175 or 800-344-3860 Toll Free USA/Canada Fax: 303-675-2176 or 800-344-3867 Toll Free USA/Canada Email: orderlit@onsemi.com

N. American Technical Support: 800-282-9855 Toll Free USA/Canada Europe, Middle East and Africa Technical Support:

Phone: 421 33 790 2910 Japan Customer Focus Center Phone: 81-3-5817-1050

ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative

## **Mouser Electronics**

**Authorized Distributor** 

Click to View Pricing, Inventory, Delivery & Lifecycle Information:

onsemi:

FDS6982AS